
**Microscopes — Graticules for
eyepieces**

Microscopes — Réticules pour oculaires

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see the following URL: www.iso.org/iso/foreword.html.

The committee responsible for this document is ISO/TC 172, *Optics and photonics*, Subcommittee SC 5 *Microscopes and endoscopes*.

This third edition cancels and replaces the second edition (ISO 9344:2011), which has been technically revised to add ISO 10110-7 and ISO 10110-8 in the normative references; see also [Table 2](#).

Microscopes — Graticules for eyepieces

1 Scope

This document specifies dimensions and permissible material defects and processing faults for graticules with diameters of 19 mm, 21 mm and 26 mm to be used in microscope eyepieces for the purposes of measurement, assessment and comparison.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 10110-1, *Optics and photonics — Preparation of drawings for optical elements and systems — Part 1: General*

ISO 10110-3, *Optics and optical instruments — Preparation of drawings for optical elements and systems — Part 3: Material imperfections — Bubbles and inclusions*

ISO 10110-4, *Optics and optical instruments — Preparation of drawings for optical elements and systems — Part 4: Material imperfections — Inhomogeneity and striae*

ISO 10110-5, *Optics and photonics — Preparation of drawings for optical elements and systems — Part 5: Surface form tolerances*

ISO 10110-7, *Optics and photonics — Preparation of drawings for optical elements and systems — Part 7: Surface imperfection tolerances*

ISO 10110-8, *Optics and photonics — Preparation of drawings for optical elements and systems — Part 8: Surface texture; roughness and waviness*

3 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

4 Requirements

4.1 Dimensions

[Table 1](#) specifies the dimensions for Type 1 and Type 2 graticules.